Notice of References Cited

Application/Control No.

O9/851,405

Examiner

Noreen Moiduddin

Applicant(s)/Patent Under Reexamination LEE, YOUNG-SEOK

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,781,720 V	07-1998	Parker et al.	714/38
	В	US-6,457,152 V	09-2002	Paley et al.	714/738
	С	US-6,421,793	07-2002	Lester et al.	714/37
	D	US-6,067,639 . 🖊	05-2000	Rodrigues et al.	714/38
	Е	US-6,002,871	12-1999	Duggan et al.	717/135
	F	US-6,047,389	04-2000	Thai, Victor M.	714/38
	G	US-5,651,111	07-1997	McKeeman et al.	714/38
	I	US-6,286,131	09-2001	Beers et al.	717/125
	_	US-5,905,856	05-1999	Ottensooser, Avner Benjamin	714/38
	J	US-6,279,124 ⁻	08-2001	Brouwer et al.	714/38
	к	US-5,574,855	11-1996	Rosich et al.	714/41
	L	US-6,002,869	12-1999	Hinckley, David N.	717/124
	М	US-6,058,493	05-2000	Talley, Stephen C.	714/38

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	α					
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NON-PATENT DOCUMENTS

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

U.S. Patent and Trademark Office PTO-892 (Rev. 01-2001)

Notice of References Cited

Application/Control No. 09/851,405

Applicant(s)/Patent Under Reexamination LEE, YOUNG-SEOK

Examiner

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,138,112	10-2000	Slutz, Donald R.	707/2
	В	US-5,954,829	09-1999	McLain et al.	714/712
	С	US-5,045,994	09-1991	Belfer et al.	703/25
	D	US-6,041,330	03-2000	Carman et al.	707/101
	Ε	US-6,505,342	01-2003	Hartmann et al.	717/104
	F	US-6,513,133	01-2003	Campbell, David G.	714/38
	G	US-6,023,580	02-2000	Sifter, Daniel J.	717/124
	Н	US-6,185,701	02-2001	Marullo et al.	714/38
	ı	US-6,577,981	06-2003	Grey et al.	702/119
	J	US-6,507,842	01-2003	Grey et al.	707/5
	к	US-6,308,146	10-2001	La Cascia et al.	703/22
	L	US-6,189,116	02-2001	Mongan et al.	714/38
	М	US-5,754,760	05-1998	Warfield, Robert W.	714/38

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0			_		
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	http://www.semantec.de/public/photos/Automated%20testing%20of%20database%20applications.pdf
	٧	CH2742-5/0000/0829\$01.00 1989 IEEE "ATG" Test Generation Software
	w	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. 09/851,405 Examiner Noreen Moiduddin Applicant(s)/Patent Under Reexamination LEE, YOUNG-SEOK Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,249,882	06-2001	Testardi, Rich P.	714/38
	В	US-			
	С	US-			
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	H	US-			
	ı	US-			
	J	US-			
	к	US-			
	٦	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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